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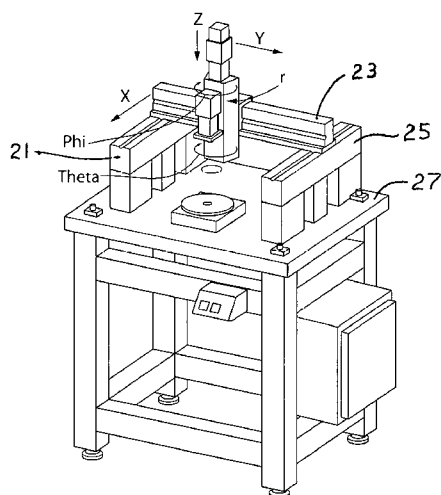


FIG. 2

(57) Abstract: A machine featuring a treatment tool that grinds a surface to a desired profile, imparts a desired roughness to that surface, and removes contamination from the surface, the machine configured to control multiple independent input variables simultaneously, the controllable variables selected from the group consisting of (i) velocity, (ii) rotation, and (iii) dither of the treatment tool, and (iv) pressure of the treatment tool against the surface. The machine can move the treatment tool with six degrees of freedom.

TITLE

Machine for finishing a work piece

CROSS-REFERENCE TO RELATED APPLICATION(S)

[0001] This patent document claims the benefit of United States Provisional Patent Application No. 62/205,648, entitled “Machine for finishing a work piece, and having a highly controllable working head”, filed on August 14, 2015 in the name of inventors Edward Gratrix et al. Where permitted, the entire contents of this provisional patent application are incorporated by reference herein.

STATEMENT REGARDING U.S. FEDERALLY SPONSORED RESEARCH

[0002] None.

TECHNICAL FIELD

[0003] The instant invention pertains to machines that have a treatment tool for processing (e.g., grinding/lapping/polishing/texturing) a work piece so that a surface of the work piece has a desired elevation or profile (i.e., a “figure”), and desired texture (roughness/smoothness). The treatment tool may be part of a larger working head assembly.

BACKGROUND ART

[0004] Chucks, such as pin chucks, are used to hold flat components for processing. The most common use is to hold wafers (Si, SiC, GaAs, GaN, Sapphire, other) during processing to yield a semiconductor device. Other uses include holding substrates during the fabrication of flat panel displays, solar

cells and other such manufactured products. These chucking components are known by many names, including wafer chucks, wafer tables, wafer handling devices, etc.

[0005] The use of pins on these devices is to provide minimum chuck-to-substrate contact. Minimum contact reduces contamination and enhances the ability to maintain high flatness. The pin tops need to have low wear in use to maximize life and precision. The pin tops also need to be low friction so the substrate easily slides on and off, and lies flat on the pins.

[0006] A pin chuck consists of a rigid body with a plurality of pins on the surface on which the substrate to be processed (e.g., Si wafer) rests. The pins exist in many geometries, and go by many names including burls, mesas, bumps, proud lands, proud rings, etc.

[0007] Regardless of whether the chuck is of the “pin” type or not, the surface that supports whatever is to be chucked (e.g., a semiconductor wafer) needs to be flat to a very high degree of precision. In the case of semiconductor lithography, the flatness is measured in nanometers (nm).

[0008] Machines exist, for example, those used in a “deterministic” fashion, to locally correct errors in flatness (surface elevation). Some techniques for this deterministic correction include, but not limited to, Ion Beam Figuring (IBF), Magneto Rheological Finishing (MRF), and computer controlled polishing (CCP). As used herein, the phrase “deterministic correction” means that figure, elevation or roughness data as measured for example, by an interferometer or profilometer, is fed into a finishing machine such as a lapping machine. The input may consist of one or more algorithms for optimizations such as

convolution or transforms to optimize the tool path or footprint in such a manner that the machine most rapidly converges to the desired target shape with a minimal amount of time, cost or risk. It effectively treats those areas of the work piece that are in error and need processing (e.g., grinding, lapping or texturing), while minimizing the effort spent working on areas that are not in need or alteration. The machine does not automatically treat the entire surface of the work piece.

[0009] The instant invention is not limited to machines that operate deterministically, but it will focus on those that employ physical contact of a tool here termed a “treatment tool” with the surface of a work piece to be processed to physically remove material from the work piece through grinding, lapping, texturing and/or polishing.

[0010] Figure 1 illustrates an example of a prior art machine. The work piece is mounted on a shaft “theta” that rotates, while treatment tool is mounted on a fixture that can move radially R with respect to the theta rotating axis. Thus, there are here two degrees of freedom of the treatment tool relative to the work piece: radius, denoted by “R”, and rotation of the work piece, denoted by “theta”.

[0011] One problem with this “R-theta” arrangement is that the treatment tool cannot process regions on the work piece that are very close to, or at, the center of the theta axis.

[0012] The machine of the instant invention addresses this problem, and provides a solution.

DISCLOSURE OF THE INVENTION

[0013] A machine featuring a treatment tool that contacts the surface of a work piece to grind that surface to a desired profile, impart a desired roughness to that surface, and remove contamination from the surface. The machine is configured to control multiple independent input variables simultaneously, the controllable variables selected from the group consisting of (i) velocity, (ii) rotation, and (iii) dither of the treatment tool, and (iv) pressure of the treatment tool against the surface. The machine can move the treatment tool with six degrees of freedom.

BRIEF DESCRIPTION OF THE DRAWINGS

[0014] Figure 1 is a prior art machine showing a simple R - theta geometry

[0015] Figure 2 is an embodiment of the machine of the present invention showing 6 degrees of freedom holding the tool and work piece

[0016] Figure 3 is a cross-sectional schematic view of the working head that can be used in connection with the instant machine.

[0017] Figures 4A and 4B show an interferometer map and surface elevation trace, respectively, for a wafer chuck of Example 1 featuring a “trench” and debris built up along the trench.

[0018] Figures 5A and 5B show an interferometer map and surface elevation trace, respectively, for the wafer chuck of Example 1 following a cleaning treatment.

[0019] Figure 6 is a graph of r-phi coordinates superimposed on X-Y Cartesian coordinates, showing that every point in the Cartesian coordinate system can be described by coordinates given in the r-phi system, thus emulating machines that move exclusively in a cartesian manner such as a stepper.

[0020] Figures 7A and 7B show an interference map and surface elevation trace, respectively, for a wafer chuck of Example 2 exhibiting a “W” shaped wear profile.

[0021] Figures 8A and 8B show an interference map and surface elevation trace, respectively, for the wafer chuck of Example 2 showing how dither of the treatment tool ameliorates the “W” shaped wear profile.

[0022] Figure 9 is a flowchart showing how a cleaning operation may be automated.

MODES FOR CARRYING OUT THE INVENTION

[0023] A machine having a treatment tool that grinds a surface to a desired profile imparts a desired roughness to that surface, and removes contamination in a single operation. The treatment tool, which may be part of a larger assembly sometimes referred to as a “working head”, features a flat surface configured to contact and abrade the surface of the work piece as the treatment tool passes over it. The treatment tool may have about the same hardness as the work piece. Visually, the treatment tool may have the appearance of a disc. Alternatively, it may appear as an annulus, ring or toroid. If shaped as an annulus or ring or toroid, the space inside or within the annular space may contain a second treatment tool. Further, the treatment tool may feature a

plurality of rings or toroids gathered or assembled together, and collectively defining a common flat surface.

[0024] The machine may be operated or programmed to function or respond deterministically to inputted data such as interferometer or profilometer data reporting on the elevation and/or roughness of a surface. In response to this inputted data, the machine directs the treatment tool to operate only on those spots or regions of the surface that require treatment.

[0025] In a first aspect of the invention, the treatment tool may have a number of degrees of freedom. First, it may translate in three dimensions, for example, along three orthogonal axes. Next, it may be mounted or attached to a shaft that can rotate. Further, the treatment tool can be mounted on the rotational axis of the shaft, or it can be mounted off-axis; that is, it can be mounted a certain distance away radially from said axis. Still further, the treatment tool can move radially with respect to the rotational axis. Additionally, the machine can be configured to impart “dither” to the treatment tool.

[0026] These degrees of freedom may be better illustrated with respect to the drawings.

[0027] Figure 1 illustrates a prior art machine. Here, there are two degrees of freedom: radius, denoted by “R”, and rotation of the work piece, denoted by “theta”.

[0028] The machine of the present invention also has these two degrees of freedom, as depicted in Figure 2. In addition, the present machine may translate the treatment tool and tool in three dimensions, for example, along “x”, “y” and

“z” axes, which may be orthogonal to each other. Next, it may be mounted or attached to a shaft that can rotate. Such rotation may be designated as “phi”. Thus, the present machine has four additional degrees of freedom beyond the two identified in the prior art machine of Figure 1. The priority document to the instant patent application contains a photograph of the machine.

[0029] Power for the various motions may be supplied by electric motor(s), which may be stepping motors or linear motors or common the art. Rails 21, 23, 25 mounted to table 27 may help guide the motions in the X and Y-directions. The rails may have mechanical contact bearings or air bearings or other low friction techniques known in the art.

[0030] Figure 3 is a cross-sectional schematic view of a “working head” 30 that can be used in connection with the instant machine. Treatment tool 134 is attached to shaft 138 whose longitudinal axis may be termed the “U” axis. The attachment may be one of minimal constraint, such as a ball-and-socket joint, or it may be at least rotationally constrained so that treatment tool 134 rotates when the U axis rotates. The U axis does not apply pressure of the treatment tool against the work piece. Rather, this pressure is applied by dead weight load 131. Rotational movement of the working head 30 is provided by input shaft 130 which defines an axis termed the “B” axis. The U axis and the B axis are firmly connected to one another through U axis adjustment block 132. This adjustment block is slotted on the bottom to allow offset adjustment of the U axis relative to the B axis. This is shown by means of adjuster screw 133. The adjuster screw may be adjusted so that the U and B axes are perfectly aligned (co-axial), or offset by an amount r (the radial offset).

[0031] Additionally, the machine can be configured to impart “dither” to the treatment tool. The nature of the dither can be random, orbital or linear. One way to impart such dither to the treatment tool is to adjust the adjuster screw so that the U axis is slightly offset from the B axis (slight amount of r), allowing the toroid to circulate in a manner such that the footprint over an undulation or dither is more controlled and smooth.

[0032] The treatment tool is 27 mm in diameter. By outward appearance, it is a disc, but in reality it has a slight toroidal shape so that when it is brought into contact with the flat surface, the area of contact is not that of a disc but instead is a circle or annulus.

[0033] The same treatment tool may be used in cleaning, profiling and roughening modes, depending upon how the tool is used. For example, given a 27mm diameter tool fabricated from reaction bonded silicon carbide, for cleaning debris off of a wafer chuck of similar hardness, a dead weight loading of 5-50 grams, and a tool velocity of 5-30 mm/sec may be used. For profiling (e.g., flattening) a surface, the loading may be 100-175 grams, and the tool velocity may be 20-50 mm/sec. For imparting surface roughness, the tool loading may be in excess of 150 grams, and the tool velocity relative to the surface being processed may be 20-50 mm/sec.

[0034] The treatment tool may be provided in different sizes (diameter or effective diameter), depending on the size of the features or region on the work piece to be processed. For example, a smaller diameter treatment tool (for example, about 10 mm) may be used to treat recessed regions on a wafer chuck, such as the vacuum seal ring on a vacuum chuck.

[0035] Moreover, the machine can be configured to house more than one working head, and have a tool changer to swap out one working head for a different one.

[0036] In addition to the spatial degrees of freedom, and in a second aspect of the invention, the machine can be designed or programmed to respond to a number of other independent variables, which variables can be inputted to the machine simultaneously. In particular, the pressure that the treatment tool applies against the surface to be treated can be controlled, as can the amplitude and frequency of treatment tool dither. Figures 2 and 3 show the tool being mounted at a distance radius “r” from the center of the rotational shaft. Since “r” is one of the degrees of freedom, so the machine can move the tool along this radius. Additionally, the velocity of the treatment tool can be controlled, both in terms of the angular or rotational velocity of the shaft, as well as the translational velocity along the radius, and the translational velocity along the x, y and z axes.

[0037] The treatment tool component of the working head may be minimally constrained. That is, its orientation with respect to the surface to be treated is not fixed or prescribed. Rather, the treatment tool orients itself, or conforms to the surface, once it is brought into contact with the surface to be treated.

[0038] In a second aspect of the invention, existing machines can be modified with a “bolt-on” module to upgrade the capabilities of other machines machine. The module would be incorporated into an existing precision machine tool, such as a semiconductor lithography machine. This would allow the user of the tool to in-situ correct the wafer chucks without removing them from the lithography

machine. This would reduce cost, enhance productivity, and allow real-time correction to constantly maintain like-new precision. For example, the treatment tool of the existing machine can be replaced with the Applicant's minimally constrained treatment tool. To further assist in having the treatment tool conform to the surface to be treated, the tool can be provided where the contacting surface is in the form of a ring, annulus or toroid. A further upgrade may include replacing the existing treatment tool with one having about the same hardness as the work piece. For example, if the work piece is a silicon carbide (SiC) wafer chuck, the substitute treatment tool can be made of SiC, or contain SiC, such as in the form of reaction-bonded SiC. A still further upgrade may include replacing the rotating treatment tool of a prior art machine with the working head of the present invention. Among the advantages flowing from this retrofit is the ability to apply dither, as well as the ability to approximate Cartesian (X-Y) motions using radial and rotational motions (r-phi), to be discussed in further detail below.

[0039] Moreover, since Applicant has discovered that changing the pressure at which the treatment tool contacts the surface to be treated changes the mode of operation from de-contamination to processing, that is, grinding and/or modifying surface roughness, the bolt-on module includes a means for changing the application pressure of the treatment tool. The means for controlling the pressure could be in the form of software. Again, the application pressure can be controllably changed as a function of time and/or location of the treatment tool on the surface being treated. Another upgrade may consist of the module providing software or other instructions to the machine to controllably vary the velocity of translation or rotation of the treatment tool.

EXAMPLES

[0040] Aspects of the present invention will now be described with reference to the following examples.

Example 1: Cleaning a wafer chuck using X and Y motions

[0041] This Example shows how a treatment tool of the present invention can be used to clean debris off of the support surface of a wafer chuck using only X and Y orthogonal motions of the treatment tool.

[0042] Figures 4A and 4B show an interferometer map and surface elevation trace, respectively, for a wafer chuck of Example 1 featuring a “trench” and debris built up along the trench. In particular, the surface elevation traces of Figure 4B are taken along the lines identified in Figure 4A (the interferometer map) as “Slice1” and “Slice 2”. Both of these slices show peaks or humps, corresponding to built-up debris. The accumulation of debris is typical or common in semiconductor processing.

[0043] The wafer chuck supporting surface was then treated with the 6-axis machine of the present invention using a working head containing a treatment tool described above, and operated under the cleaning conditions described above. However, only 2 of the 6 axes of the machine were used, namely, motions in a Cartesian coordinate system: X and Y directions at right angles to one another.

[0044] The results of this cleaning treatment are shown in Figure 5. Again, the figure shows an interference map for the entire wafer chuck surface in Figure 5A, and surface elevation traces for Slices 1 and 2 in Figure 5B. A number of

features stand out regarding Figure 5B. First, the peaks or humps have been eliminated, indicating successful removal of debris. Second, the depression in Slice 1 reveals the presence of a trench in the wafer chuck surface. Third, the absence of a depression in Slice 2 indicates or suggests that the trench is present only on one side of the wafer chuck.

[0045] Thus, the treatment tool of the present invention has been used successfully to clean debris off of the support surface of a wafer chuck using only motions of the tool in orthogonal X and Y-directions. Thus, prior art machines having X and Y-motion capabilities could be retrofitted with the treatment tool of the present invention to conduct similar cleaning/decontamination.

[0046] In addition, prior art R-theta machines likewise could be retrofitted with the working head of Figure 3 to conduct this cleaning operation. Specifically, and as depicted in Figure 6, the X and Y orthogonal motions of the treatment tool can be approximated with r and phi (or “B” axis) motions. Specifically, every point in the X-Y cartesian coordinate system can be represented by specifying the r and phi coordinates. The smaller the increments of r and phi, the closer the approximation to X and Y orthogonal motion. Here, the B axis rotation (phi) and the radial offset, r, could be controlled by stepper motors, which could be controlled by programmable controllers. Figure 9 provides a flowchart and block diagram for an automated cleaning operation.

Example 2: Effect of “dither” on the wear profile

[0047] This Example shows one use for the “dither” feature of the working head, and is made with reference to Figures 7 and 8.

[0048] Figures 7A and 7B show an interference map and surface elevation trace, respectively, for a wafer chuck of Example 2

[0049] A “toroidal” shaped treatment tool having about the same hardness as the wafer chuck surface being processed was moved back and forth along a single axis (for example, the “Y” axis with an applied pressure and velocity appropriate for profiling (changing surface elevation)). Again, the toroidal shape means that the contact region between the treatment tool and the wafer chuck was a circle, annulus, or ring. A surface elevation profile was then made of a “slice” of the wear path. A total of three such wear tracks and slices were made. The results are displayed as the interference map of Figures 7A and the surface elevation traces of Figure 7B, respectively.

[0050] Slice 2 showed the greatest amount of material removed from the chuck surface, as evidenced both by the darkest wear path in the interference map, as well as by the deepest trace of the three slices in the surface elevation plots of Figure 7B. Moreover, the cross-section of the wear path exhibits something resembling a “W” shape: moving away from the deepest part of the wear path, the elevation first levels out somewhat before continuing to rise to join up with the unaffected part of the wafer chuck adjacent to the wear track.

[0051] Figures 8A and 8B now show what happens when dither is applied to the treatment tool. The above test was repeated on a new, flat wafer chuck surface. Except for the application of dither, all of the operating parameters were kept the same as before. All three slices of the three wear tracks show significant wear (removal) of wafer chuck material. However, the cross-section of the wear tracks is much different. The “shoulders” are now gone, and each

wear track has a cross-section resembling a shallow “U” shape, or closer to a Gaussian which is smoother function so as to not impart the undulations of the 'W'.

INDUSTRIAL APPLICABILITY

[0052] A single working head or treatment tool can grind, impart roughness, and remove contamination such as grinding debris from a surface to be treated. This is so because a light pressure will remove the contamination but will not modify the profile or alter the roughness of the surface. Higher pressures result in removal of substrate material from the surface being treated, not just contamination.

[0053] If the working head or treatment tool is sufficiently small in effective diameter it can be used to treat surfaces at different elevations. This is useful because in a wafer chuck having a seal ring, and pins, the seal ring is at a lower elevation than are the pin tops. A sufficiently small tool will fit within the width of the seal groove. Before treating the seal groove, however, the tool can be used to process the pin tops, for example, to correct flatness and to impart the required degree of roughness. This would be performed at relatively high application pressures. If this treatment is conducted deterministically and if the elevation map produced by the interferometer does not show too much area requiring grinding or lapping, the small diameter tool will be adequate to the task without taking too long to treat the area(s). After the tool finishes the grinding/lapping treatment, it can then be moved into the seal groove, and move circumferentially along the seal ring groove. At light application pressures, it will remove contamination but not remove substrate material, which would create additional contamination.

[0054] The “theta” and “phi” rotational axes of the instant machine typically are separate, distinct axes. As such, the treatment tool can be positioned over the center of the work piece, permitting this region of the work piece to be processed. In contrast, the treatment tool of the R-theta two degrees-of-freedom machine of the prior art cannot process this central region.

[0055] An artisan of ordinary skill will appreciate that various modifications may be made to the invention herein described without departing from the scope or spirit of the invention as defined in the appended claims.

CLAIMS

What is claimed is:

1. A machine comprising a treatment tool that grinds a surface to a desired figure, imparts a desired roughness to that surface, and removes contamination in a single operation.
2. The machine of claim 1, wherein said treatment tool is a single tool.
3. The machine of claim 1, configured to operate on the surface deterministically.
4. The machine of claim 1, wherein said treatment tool is minimally constrained.
5. The machine of claim 1, wherein said treatment tool comprises a geometry selected from the group consisting of a ring, an assemblage of rings, and a ring with a treating surface located within an annulus of said ring.
6. The machine of claim 1, wherein said treatment tool is mounted to a rotatable shaft.
7. The machine of claim 6, wherein said treatment tool is mounted offset radially with respect to a longitudinal axis of said rotatable shaft.
8. The machine of claim 1, further comprising means for translating said treatment tool along at least one of three orthogonal directions.

9. The machine of claim 1, further comprising means for controlling a pressure of said treatment tool against the surface.

10. The machine of claim 9, wherein said pressure is controlled as a function of at least one of (i) time and (ii) location of said treatment tool on the surface.

11. The machine of claim 6, further comprising means for controlling a rotational velocity of said shaft.

12. The machine of claim 7, further comprising means for controlling a velocity of said treatment tool along said radius.

13. The machine of claim 8, further comprising means for controlling a velocity of said treatment tool along said orthogonal directions.

14. The machine of claim 1, further comprising a means for imparting dither to said treatment tool.

15. The machine of claim 14, further comprising means for controlling at least one of amplitude and frequency of said dither.

16. The machine of claim 1, further comprising a tool changer.

17. The machine of claim 1, further comprising more than one treatment tool, whereby said machine is able to swap out one treatment tool for another.

18. The machine of claim 1, configured to process a second surface that is at a different elevation than a first surface.

19. The machine of claim 11, wherein said surface is a first surface, said machine further configured to process a second surface that is recessed relative to said first surface.

20. A machine comprising a single treatment tool that grinds a surface to a desired figure, imparts a desired roughness to that surface, and removes contamination from the surface, said machine configured to control multiple independent input variables simultaneously, said controllable variables selected from the group consisting of (i) velocity, (ii) rotation, and (iii) dither of said treatment tool, and (iv) pressure of said treatment tool against the surface.

21. In a machine comprising a known treatment tool configured to finish a surface of a work piece, a supplemental module that replaces said known treatment tool with a different treatment tool that comprises at least one of the properties selected from the group consisting of (i) approximate same hardness as that of the work piece, and (ii) having a ring, annulus or toroidal shape.

22. In a machine comprising a known treatment tool configured to finish a surface of a work piece, a supplemental module comprising instructions that instruct said machine to controllably vary at least one of (i) a pressure that the treatment tool applies to the work piece, and (ii) a velocity of the treatment tool.

23. The method of either of claims 21 or 22, wherein said machine comprises a semiconductor lithography machine.

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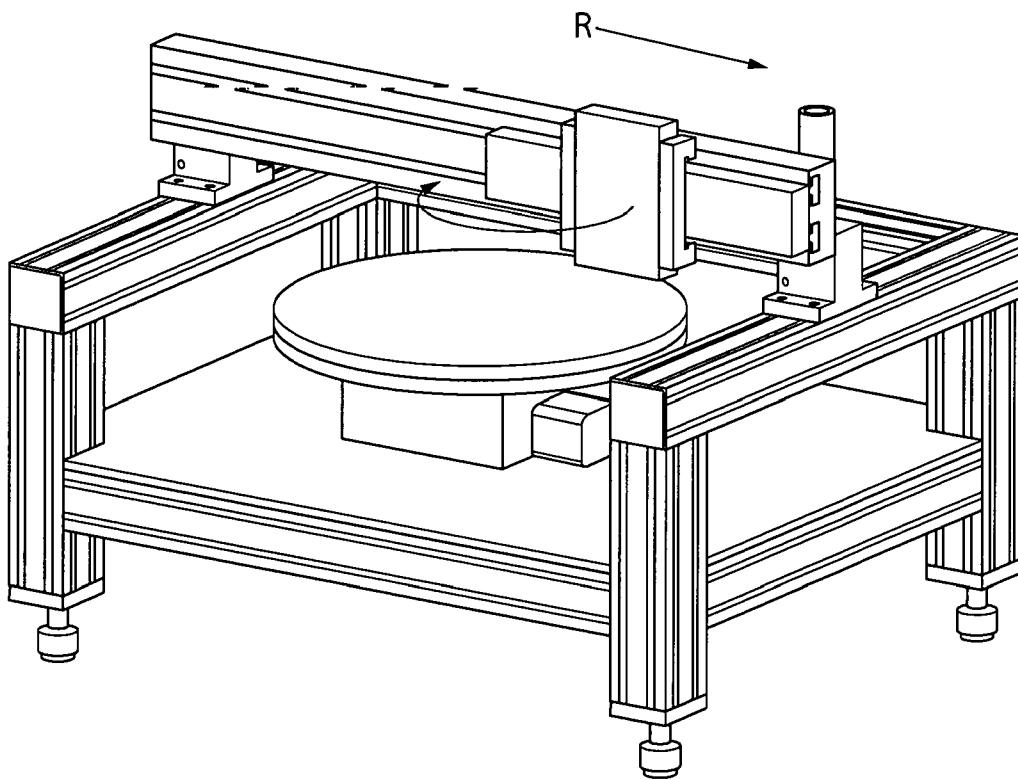


FIG. 1
(PRIOR ART)

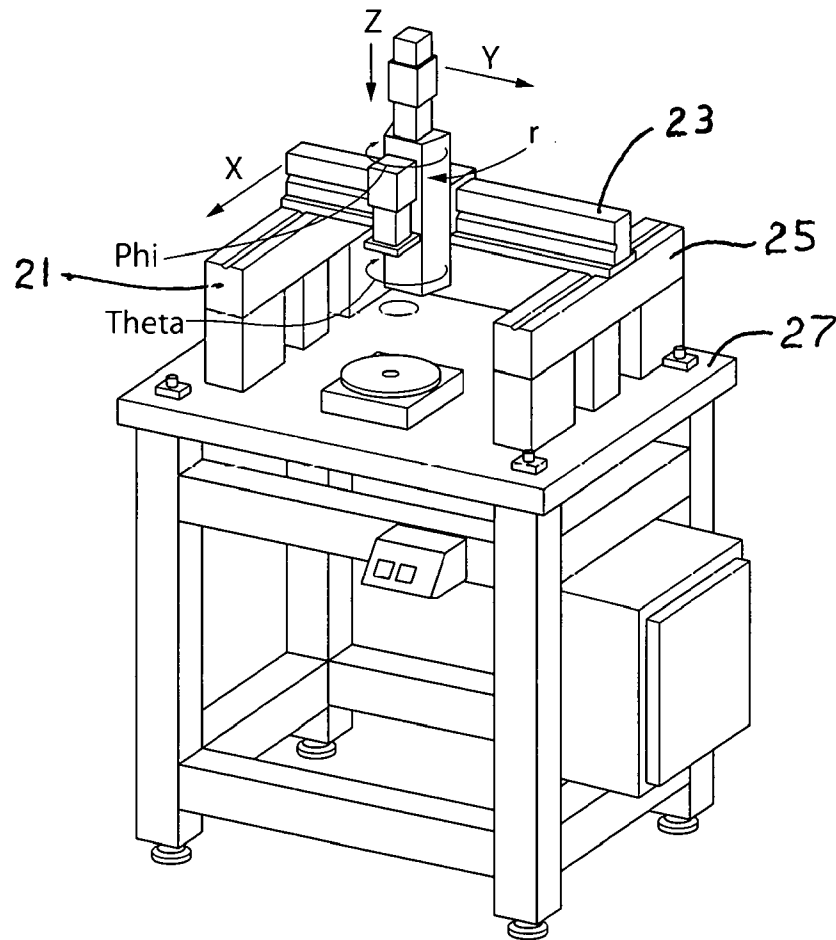


FIG. 2

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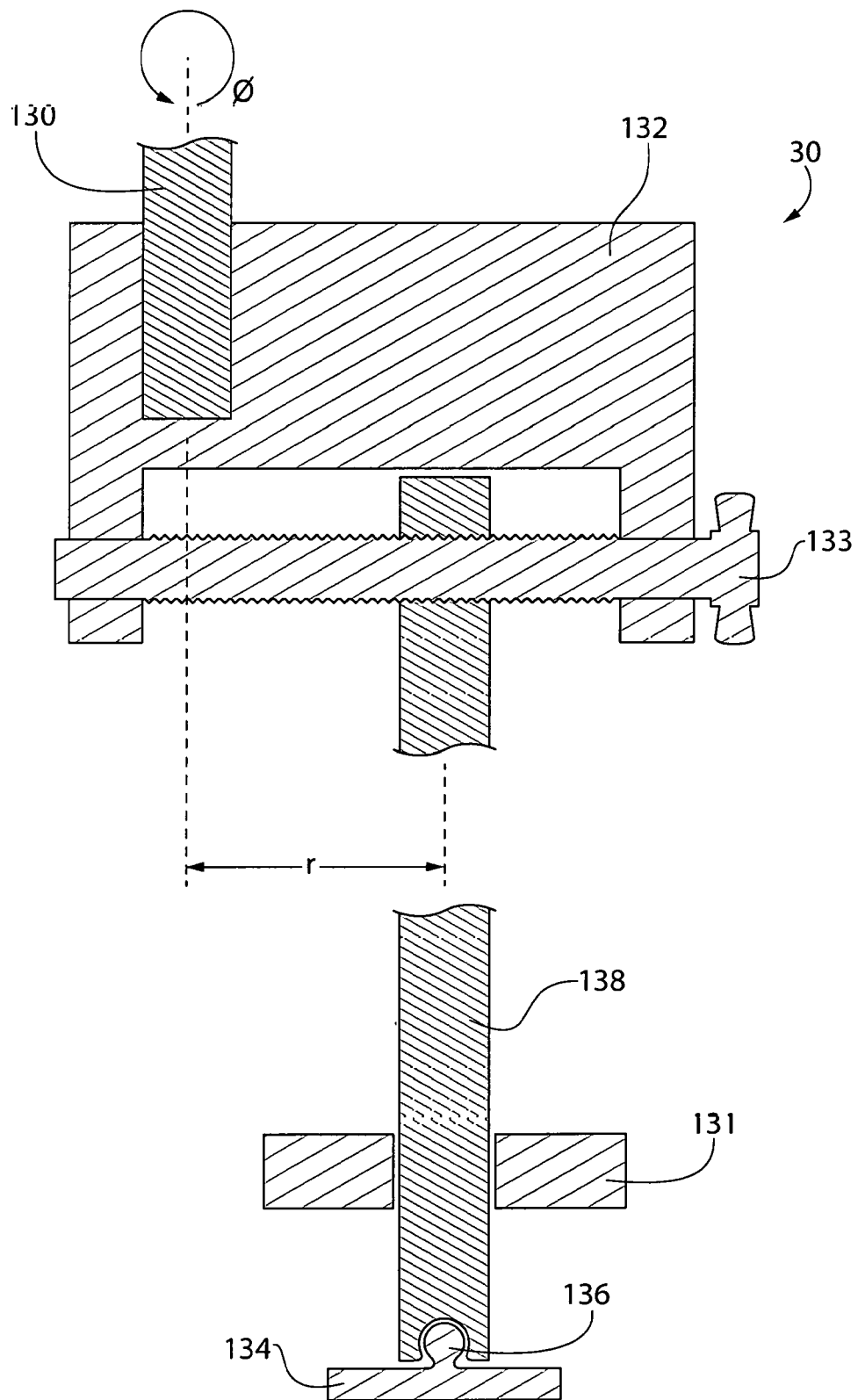


FIG. 3

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PV 333.572nm
RMS 65.937nm

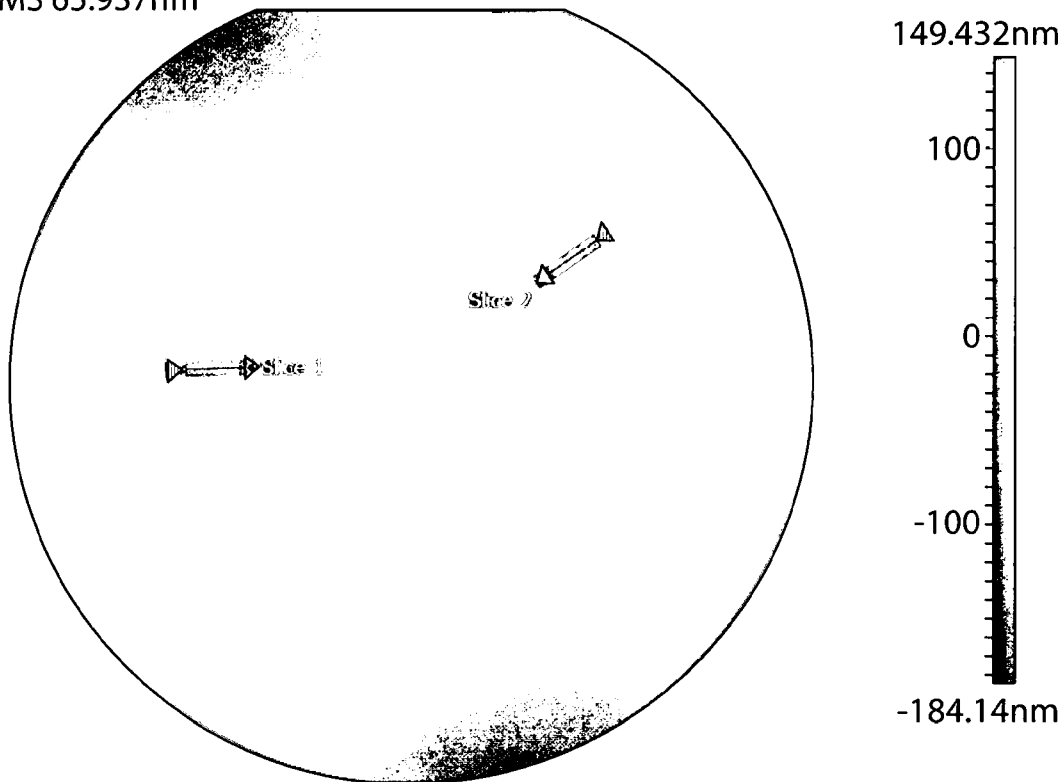


FIG. 4A

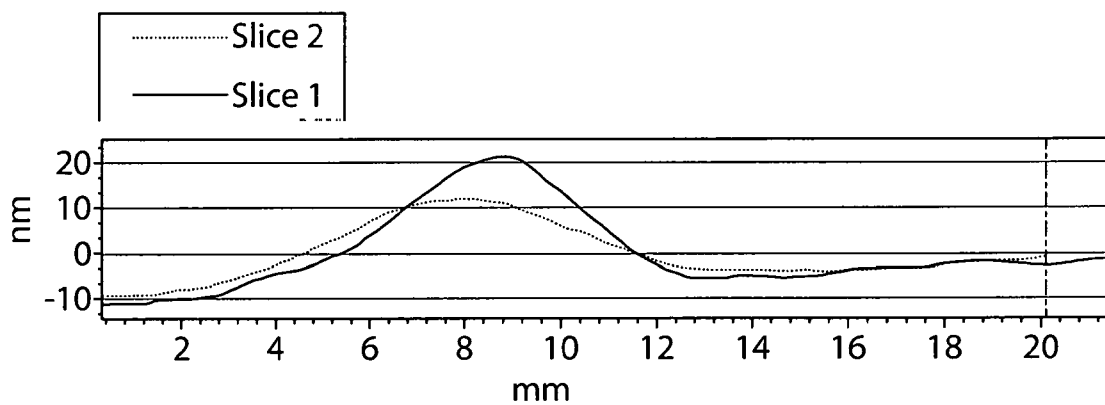


FIG. 4B

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PV 340.176nm
RMS 68.154nm

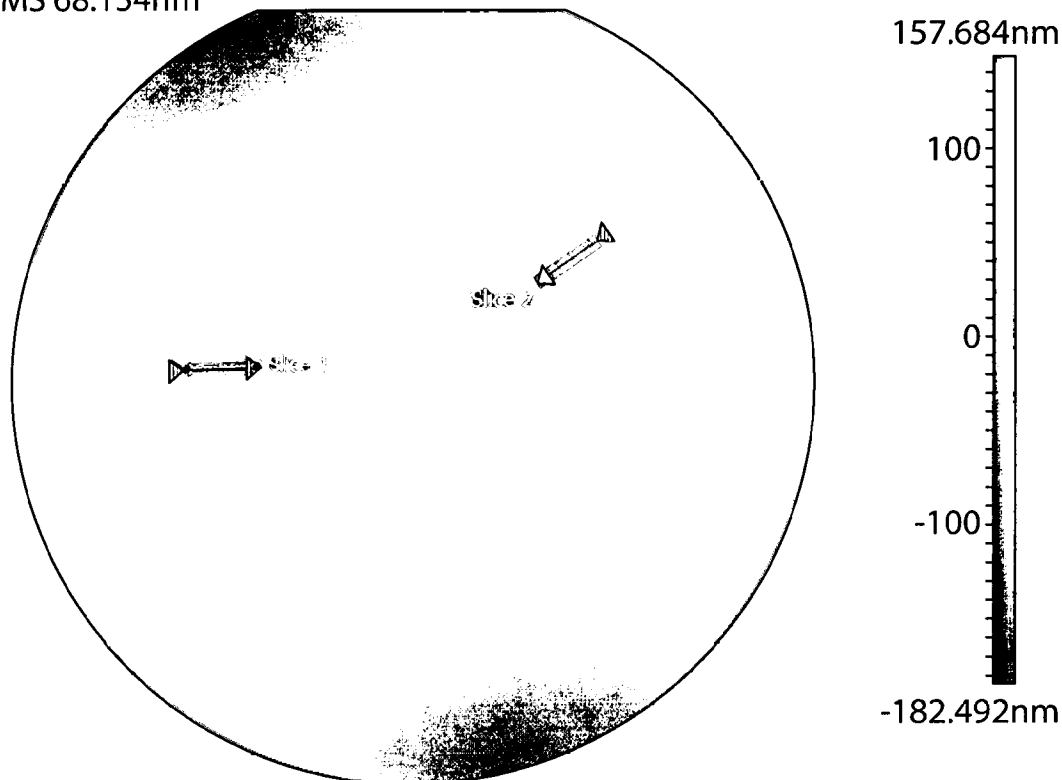


FIG. 5A

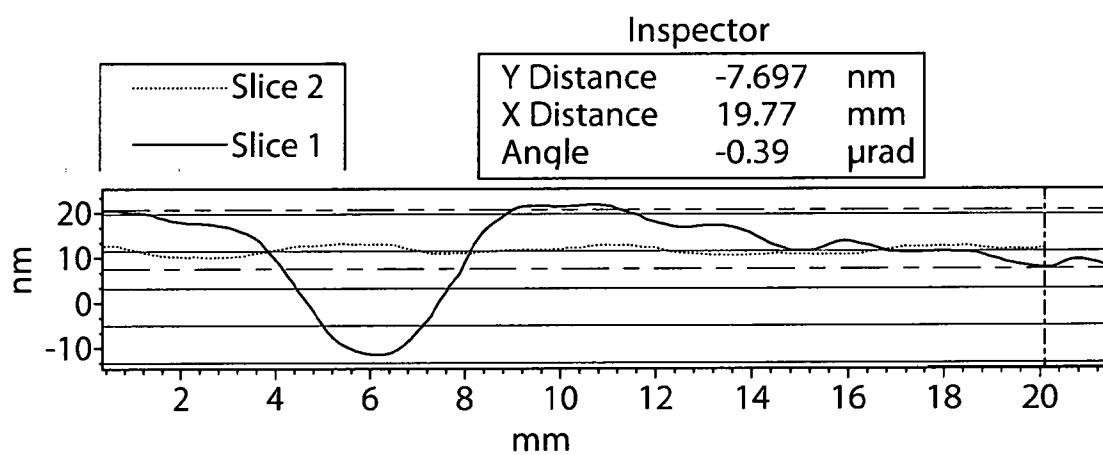


FIG. 5B

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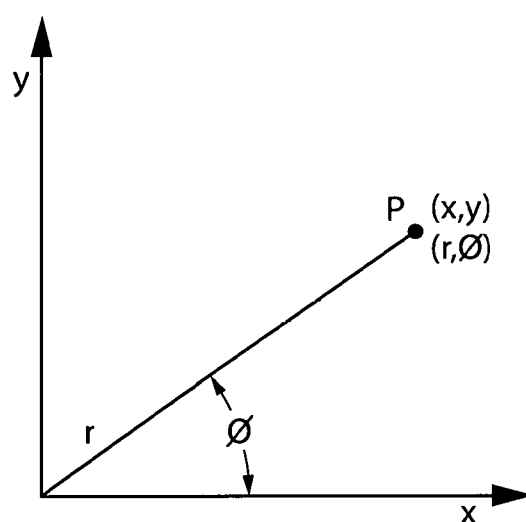


FIG. 6

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PV 340.176nm
RMS 68.154nm

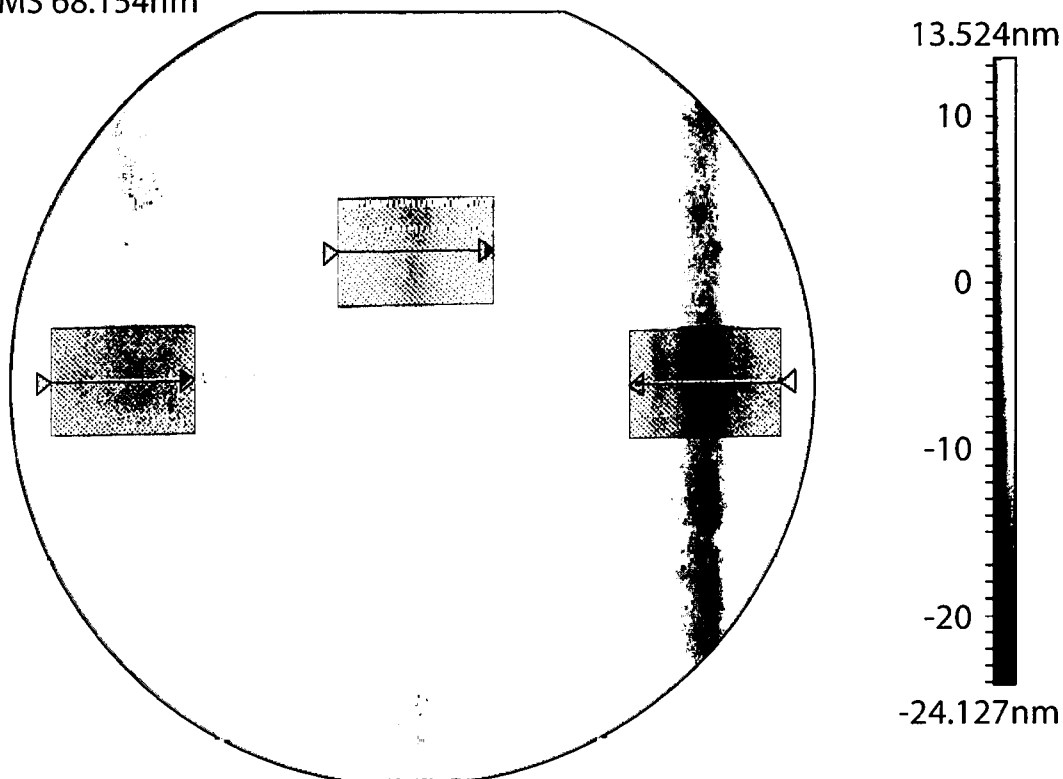


FIG. 7A

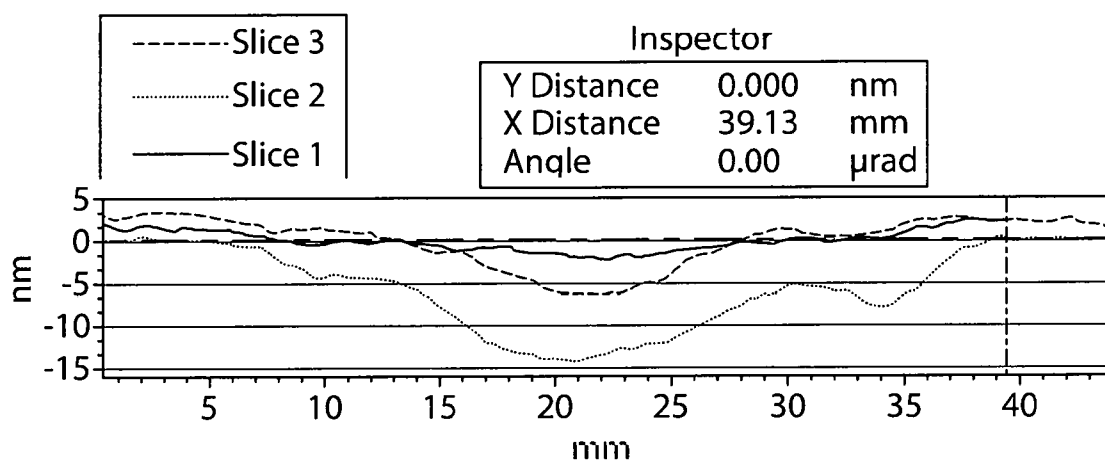


FIG. 7B

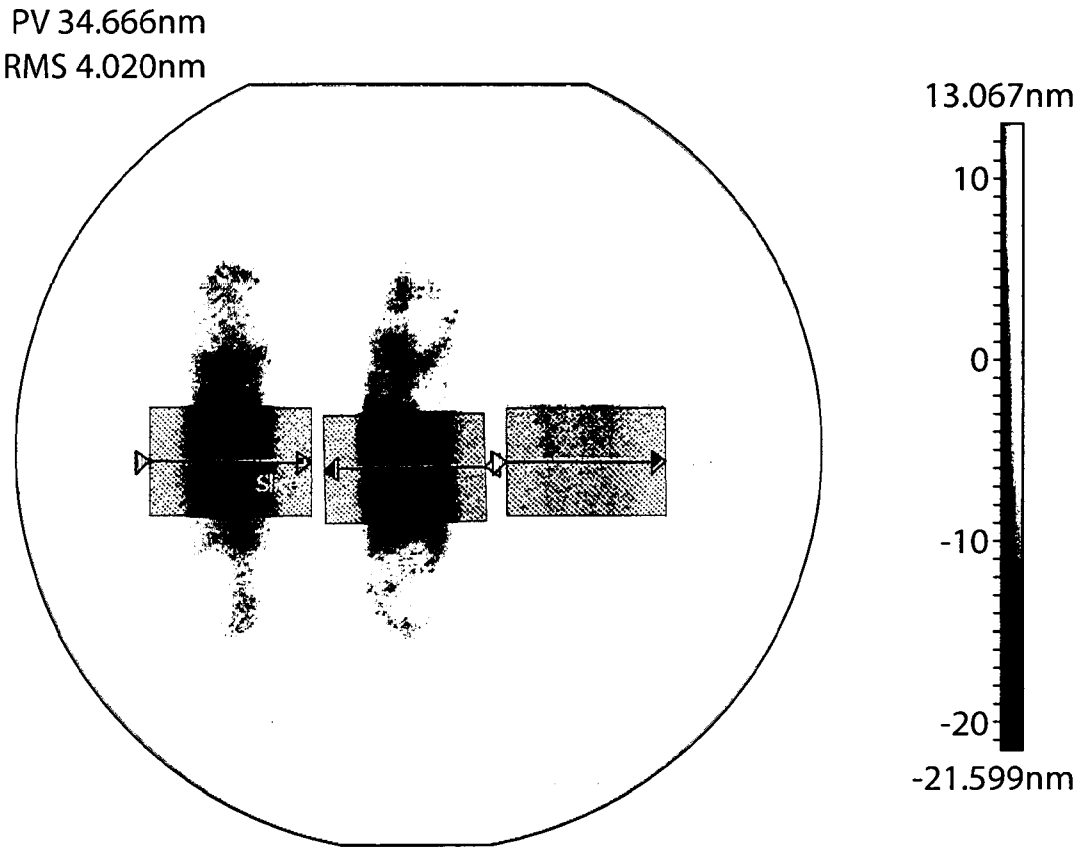


FIG. 8A

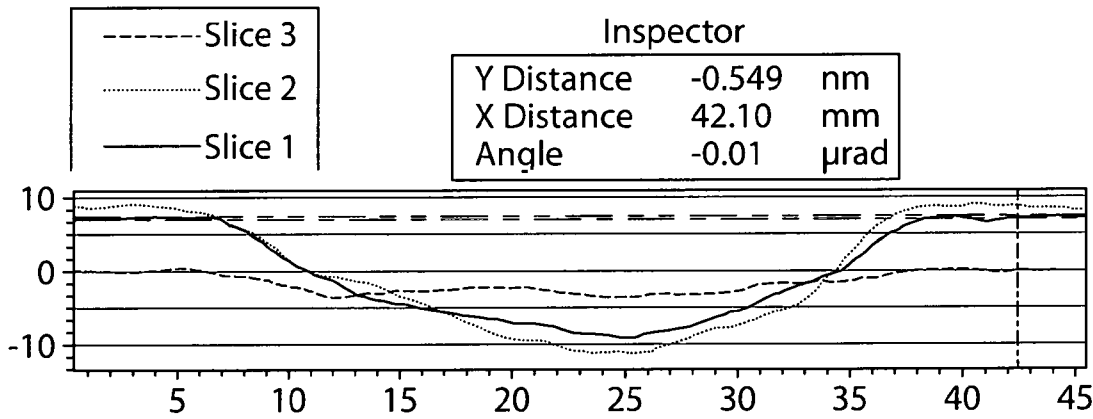


FIG. 8B

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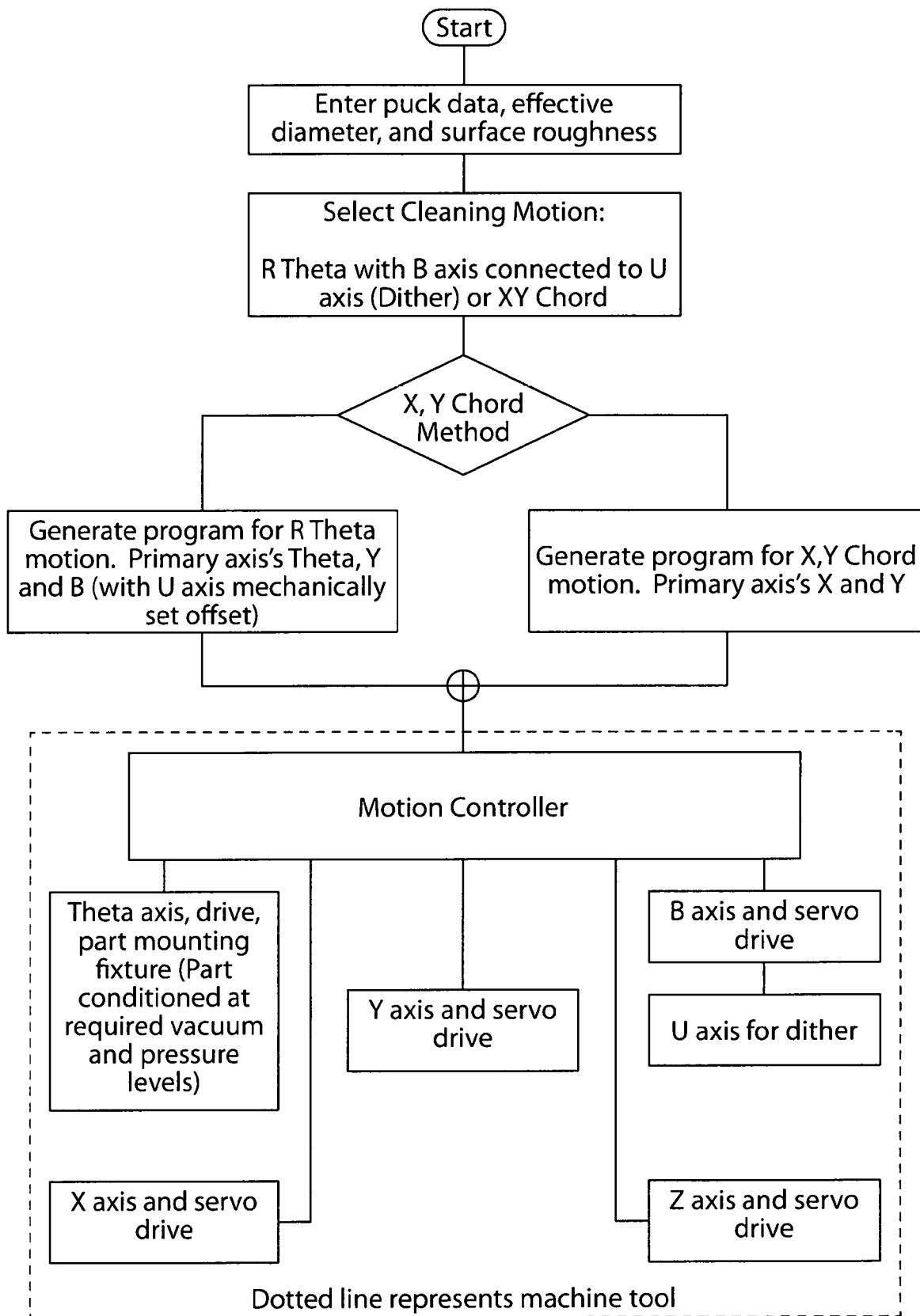


FIG. 9

INTERNATIONAL SEARCH REPORT

International application No.

PCT/US16/46439

Box No. II Observations where certain claims were found unsearchable (Continuation of item 2 of first sheet)

This international search report has not been established in respect of certain claims under Article 17(2)(a) for the following reasons:

1. ☐ Claims Nos.:
because they relate to subject matter not required to be searched by this Authority, namely:

2. ☐ Claims Nos.:
because they relate to parts of the international application that do not comply with the prescribed requirements to such an extent that no meaningful international search can be carried out, specifically:

3. ☐ Claims Nos.:
because they are dependent claims and are not drafted in accordance with the second and third sentences of Rule 6.4(a).

Box No. III Observations where unity of invention is lacking (Continuation of item 3 of first sheet)

This International Searching Authority found multiple inventions in this international application, as follows:

---Continued Within the Next Supplemental Box---

1. ☐ As all required additional search fees were timely paid by the applicant, this international search report covers all searchable claims.
2. ☐ As all searchable claims could be searched without effort justifying additional fees, this Authority did not invite payment of additional fees.
3. ☐ As only some of the required additional search fees were timely paid by the applicant, this international search report covers only those claims for which fees were paid, specifically claims Nos.:
4. ☒ No required additional search fees were timely paid by the applicant. Consequently, this international search report is restricted to the invention first mentioned in the claims; it is covered by claims Nos.:
1-20, 22, 23/22

Remark on Protest

- ☐ The additional search fees were accompanied by the applicant's protest and, where applicable, the payment of a protest fee.
- ☐ The additional search fees were accompanied by the applicant's protest but the applicable protest fee was not paid within the time limit specified in the invitation.
- ☐ No protest accompanied the payment of additional search fees.

INTERNATIONAL SEARCH REPORT

International application No.

PCT/US16/46439

A. CLASSIFICATION OF SUBJECT MATTER IPC(8) - B24B 1/00, 37/005; H01L 21/302, 21/304 (2016.01) CPC - B24B 1/00, 7/00, 37/042; H01L 21/02013, 21/02096, 21/304 According to International Patent Classification (IPC) or to both national classification and IPC		
B. FIELDS SEARCHED Minimum documentation searched (classification system followed by classification symbols) IPC(8) - B24B 1/00, 7/00, 27/033, 37/005, 37/04, 37/07, 37/12, 41/047; G03F 7/20; H01L 21/30, 21/302, 21/304, 21/64 (2016.01); CPC - B24B 1/00, 7/04, 7/07, 27/033, 37/005, 37/042, 37/07; H01L 21/0213, 21/02041, 21/02057, 21/02096, 21/302, 21/304; Y10S 438/959 Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched Electronic data base consulted during the international search (name of data base and, where practicable, search terms used) PatSeer (US, EP, WO, JP, DE, GB, CN, FR, KR, ES, AU, IN, CA, INPADOC Data); Google; Google Scholar; EBSCO; control*, var*, pressure*, velocit*, speed*, rotat*, grind*, polish*, lapping, smooth*, rough*, textur*, flatten*, clean*, remov*, contam*, surfac*, profil*, elevation*, contour*, shap*, figur*, shaft*, spindle*, simult*, deterministic*, offset*, dither*, lithograph*, semiconductor*, wafer*, substrate*		
C. DOCUMENTS CONSIDERED TO BE RELEVANT		
Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	JP H 07171747 A (RICOH CO LTD) 11 July 1995; figures 1-3; paragraphs [0006], [0009], [0012]-[0017]	1-2, 4-13, 18-20, 22
---		3, 7, 12, 14-17, 23/22
Y	US 2014/0335767 A1 (SURATWALA, T. I. et al.) 13 November 2014; paragraphs [0006], [0039]	3
Y	US 2010/0214549 A1 (CADEE, T. P. M. et al.) 26 August 2010; figure 5; paragraphs [0063]-[0065]	7, 12
Y	US 2,926,653 A (KRAFFT, F. G.) 01 March 1960; figure 1; column 1, lines 45-70; column 2, lines 40-70	14-15
Y	US 5,478,271 A (THIBAUT, B.) 26 December 1995; figure 1; column 2, lines 1-30; column 3, lines 10-25; column 5, lines 20-35	16-17
Y	US 5,969,972 A (KERSZYKOWSKI, D. et al.) 19 October 1999; column 1, lines 50-65; column 2, lines 1-20	23/22
<input type="checkbox"/> Further documents are listed in the continuation of Box C. <input type="checkbox"/> See patent family annex.		
* Special categories of cited documents: "A" document defining the general state of the art which is not considered to be of particular relevance "E" earlier application or patent but published on or after the international filing date "L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) "O" document referring to an oral disclosure, use, exhibition or other means "P" document published prior to the international filing date but later than the priority date claimed "T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention "X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone "Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art "&" document member of the same patent family		
Date of the actual completion of the international search 15 December 2016 (15.12.2016)		Date of mailing of the international search report 17 JAN 2017
Name and mailing address of the ISA/US Mail Stop PCT, Attn: ISA/US, Commissioner for Patents P.O. Box 1450, Alexandria, Virginia 22313-1450 Facsimile No. 571-273-8300		Authorized officer Shane Thomas PCT Helpdesk: 571-272-4300 PCT OSP: 571-272-7774

INTERNATIONAL SEARCH REPORT
Information on patent family members

International application No.
PCT/US16/46439

-Continued from Box No. III Observations where unity of invention is lacking-

This application contains the following inventions or groups of inventions which are not so linked as to form a single general inventive concept under PCT Rule 13.1. In order for all inventions to be examined, the appropriate additional examination fee must be paid.

Group I: Claims 1-20, 22, and 23/22 are directed toward a single treatment tool that grinds a surface to a desired figure, imparts a desired roughness to that surface, and removes contamination from the surface, said machine configured to control multiple independent input variables simultaneously, said controllable variables selected from the group consisting of (i) velocity, (ii) rotation, and (iii) dither of said treatment tool, and (iv) pressure of said treatment tool against the surface.

Group II: Claims 21 and 23/21 are directed toward a known treatment tool configured to finish a surface of a work piece, a supplemental module that replaces said known treatment tool with a different treatment tool that comprises at least one of the properties selected from the group consisting of (i) approximate same hardness as that of the work piece, and (ii) having a ring, annulus or toroidal shape.

The inventions listed as Groups I and II do not relate to a single general inventive concept under PCT Rule 13.1 because, under PCT Rule 13.2, they lack the same or corresponding special technical features.

Group I has at least a single treatment tool that grinds a surface to a desired figure, imparts a desired roughness to that surface, and removes contamination from the surface, said machine configured to control multiple independent input variables simultaneously, said controllable variables selected from the group consisting of (i) velocity, (ii) rotation, and (iii) dither of said treatment tool, and (iv) pressure of said treatment tool against the surface that Group II does not have.

Group II has at least a supplemental module that replaces said known treatment tool with a different treatment tool that comprises at least one of the properties selected from the group consisting of (i) approximate same hardness as that of the work piece, and (ii) having a ring, annulus or toroidal shape that Group I does not have.

The common technical features of Groups I and II are at least comprising a known treatment tool configured to finish a surface of a work piece and a supplemental module. These common features are disclosed by JP 7-171747 A to RICOH CO LTD (hereinafter, 'Ricoh'). Ricoh discloses a known treatment tool configured to finish a surface of a work piece (a grinding tool 1 to grind a work 12, figures 1 and 3, abstract) and a supplemental module (polishing tool 2, figures 1 and 3, abstract).

Since the common technical feature is previously disclosed by the Ricoh reference, these common features are not special and so Groups I and II lack unity.